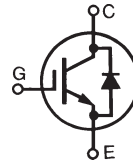


**GenX3™ 1200V  
IGBT w/ Diode**
**IXGN82N120C3H1**

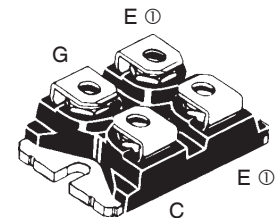
$$V_{CES} = 1200V$$

$$I_{C110} = 58A$$

$$V_{CE(sat)} \leq 3.9V$$

 High-Speed PT IGBT for  
20-50 kHz Switching


Symbol	Test Conditions	Maximum Ratings	
$V_{CES}$	$T_J = 25^\circ\text{C to } 150^\circ\text{C}$	1200	V
$V_{CGR}$	$T_J = 25^\circ\text{C to } 150^\circ\text{C}, R_{GE} = 1M\Omega$	1200	V
$V_{GES}$	Continuous	$\pm 20$	V
$V_{GEM}$	Transient	$\pm 30$	V
$I_{C25}$	$T_C = 25^\circ\text{C}$	130	A
$I_{C110}$	$T_C = 110^\circ\text{C}$	58	A
$I_{F110}$	$T_C = 110^\circ\text{C}$	42	A
$I_{CM}$	$T_C = 25^\circ\text{C}, 1\text{ms}$	500	A
<b>SSOA</b>	$V_{GE} = 15V, T_{VJ} = 125^\circ\text{C}, R_G = 3\Omega$	$I_{CM} = 164$	A
<b>(RBSOA)</b>	Clamped Inductive Load	$V_{CE} \leq V_{CES}$	
$P_C$	$T_C = 25^\circ\text{C}$	595	W
$T_J$		-55 ... +150	$^\circ\text{C}$
$T_{JM}$		150	$^\circ\text{C}$
$T_{stg}$		-55 ... +150	$^\circ\text{C}$
$V_{ISOL}$	50/60Hz	$t = 1\text{min}$	2500 V~
	$I_{ISOL} \leq 1\text{mA}$	$t = 1\text{s}$	3000 V~
$M_d$	Mounting Torque	1.5/13	Nm/lb.in.
	Terminal Connection Torque	1.3/11.5	Nm/lb.in.
<b>Weight</b>		30	g

 SOT-227B, miniBLOC  
 E153432

 G = Gate, C = Collector, E = Emitter  
 ① either emitter terminal can be used as  
Main or Kelvin Emitter

**Features**

- Optimized for Low Switching Losses
- Square RBSOA
- High Current Capability
- Isolation Voltage 2500 V~
- Anti-Parallel Ultra Fast Diode
- International Standard Package

**Advantages**

- High Power Density
- Low Gate Drive Requirement

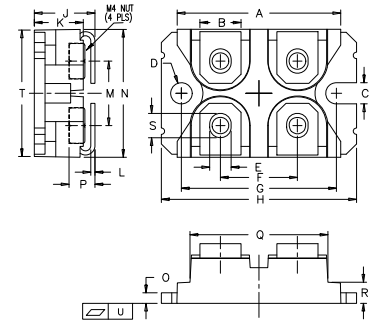
**Applications**

- Power Inverters
- UPS
- SMPS
- PFC Circuits
- Welding Machines
- Lamp Ballasts

Symbol	Test Conditions ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
$V_{GE(th)}$	$I_C = 1\text{mA}, V_{CE} = V_{GE}$	3.0		5.0 V
$I_{CES}$	$V_{CE} = V_{CES}, V_{GE} = 0V$ , Note 1 $T_J = 125^\circ\text{C}$			50 $\mu\text{A}$ 6 mA
$I_{GES}$	$V_{CE} = 0V, V_{GE} = \pm 20V$			$\pm 200$ nA
$V_{CE(sat)}$	$I_C = 82A, V_{GE} = 15V$ , Note 2		3.3	3.9 V

Symbol	Test Conditions ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
$g_{fs}$	$I_C = 60\text{A}$ , $V_{CE} = 10\text{V}$ , Note 2	38	62	S
$C_{ies}$	$V_{CE} = 25\text{V}$ , $V_{GE} = 0\text{V}$ , $f = 1\text{ MHz}$		7900	pF
$C_{oes}$			685	pF
$C_{res}$			197	pF
$Q_{g(on)}$	$I_C = 82\text{A}$ , $V_{GE} = 15\text{V}$ , $V_{CE} = 0.5 \cdot V_{CES}$		340	nC
$Q_{ge}$			55	nC
$Q_{gc}$			145	nC
$t_{d(on)}$	<b>Inductive load, <math>T_J = 25^\circ\text{C}</math></b>		30	ns
$t_{ri}$			77	ns
$E_{on}$	$I_C = 82\text{A}$ , $V_{GE} = 15\text{V}$		5.0	mJ
$t_{d(off)}$	$V_{CE} = 0.5 \cdot V_{CES}$ , $R_G = 2\Omega$		194	ns
$t_{fi}$	Note 3		100	ns
$E_{off}$			2.5	5.0 mJ
$t_{d(on)}$	<b>Inductive load, <math>T_J = 125^\circ\text{C}</math></b>		32	ns
$t_{ri}$			80	ns
$E_{on}$	$I_C = 82\text{A}$ , $V_{GE} = 15\text{V}$		6.8	mJ
$t_{d(off)}$	$V_{CE} = 0.5 \cdot V_{CES}$ , $R_G = 2\Omega$		230	ns
$t_{fi}$	Note 3		270	ns
$E_{off}$			4.0	mJ
$R_{thJC}$				0.21 $^\circ\text{C/W}$
$R_{thCK}$		0.05		$^\circ\text{C/W}$

### SOT-227B miniBLOC (IXGN)



SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	1.240	1.255	31.50	31.88
B	.307	.323	7.80	8.20
C	.161	.169	4.09	4.29
D	.161	.169	4.09	4.29
E	.161	.169	4.09	4.29
F	.587	.595	14.91	15.11
G	1.186	1.193	30.12	30.30
H	1.496	1.505	38.00	38.23
J	.460	.481	11.68	12.22
K	.351	.378	8.92	9.60
L	.030	.033	0.76	0.84
M	.496	.506	12.60	12.85
N	.990	1.001	25.15	25.42
O	.078	.084	1.98	2.13
P	.195	.235	4.95	5.97
Q	1.045	1.059	26.54	26.90
R	.155	.174	3.94	4.42
S	.186	.191	4.72	4.85
T	.968	.987	24.59	25.07
U	-.002	.004	-0.05	0.1

### Reverse Diode (FRED)

Symbol	Test Conditions ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
$V_F$	$I_F = 60\text{A}$ , $V_{GE} = 0\text{V}$ , Note 1			2.5 V
	$T_J = 150^\circ\text{C}$		1.4	1.8 V
$I_{RM}$	$I_F = 60\text{A}$ , $V_{GE} = 0\text{V}$ , $-di_F/dt = 200\text{A}/\mu\text{s}$ , $V_R = 300\text{V}$		8.3	A
$t_{rr}$			140	ns
$R_{thJC}$				0.42 $^\circ\text{C/W}$

### Notes:

1. Part must be heatsunk for high-temp  $I_{ces}$  measurement.
2. Pulse test,  $t \leq 300\mu\text{s}$ , duty cycle,  $d \leq 2\%$ .
3. Switching times & energy losses may increase for higher  $V_{CE}(\text{Clamp})$ ,  $T_J$  or  $R_G$ .

### ADVANCE TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from a subjective evaluation of the design, based upon prior knowledge and experience, and constitute a "considered reflection" of the anticipated result. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

### IXYS Reserves the Right to Change Limits, Test Conditions, and Dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents:	4,835,592	4,931,844	5,049,961	5,237,481	6,162,665	6,404,065 B1	6,683,344	6,727,585	7,005,734 B2	7,157,338B2
	4,850,072	5,017,508	5,063,307	5,381,025	6,259,123 B1	6,534,343	6,710,405 B2	6,759,692	7,063,975 B2	
	4,881,106	5,034,796	5,187,117	5,486,715	6,306,728 B1	6,583,505	6,710,463	6,771,478 B2	7,071,537	



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